

TDA7563

MULTIFUNCTION QUAD POWER AMPLIFIER WITH BUILT-IN DIAGNOSTICS FEATURES

- DMOS POWER OUTPUT
- NON-SWITCHING HI-EFFICIENCY
- HIGH OUTPUT POWER CAPABILITY $4x28W/4\Omega$ @ 14.4V, 1KHZ, 10% THD, 4x40W EIAJ
- MAX. OUTPUT POWER $4x72W/2\Omega$
- **FULL I2C BUS DRIVING:**
 - ST-BY
 - INDEPENDENT FRONT/REAR SOFT PLAY/MUTE
 - SELECTABLE GAIN 30dB 16dB (FOR LOW NOISE LINE OUTPUT FUNCTION) - HIGH EFFICIENCY ENABLE/DISABLE

 - I²C BUS DIGITAL DIAGNOSTICS
- FULL FAULT PROTECTION
- DC OFFSET DETECTION
- FOUR INDEPENDENT SHORT CIRCUIT **PROTECTION**
- CLIPPING DETECTOR PIN WITH SELECT-ABLE THRESHOLD (2%/10%)
- ST-BY/MUTE PIN
- LINEAR THERMAL SHUTDOWN
- **ESD PROTECTION**

DESCRIPTION

The TDA7563 is a new BCD technology QUAD BRIDGE

BLOCK DIAGRAM

MULTIPOWER BCD TECHNOLOGY

MOSFET OUTPUT POWER STAGE

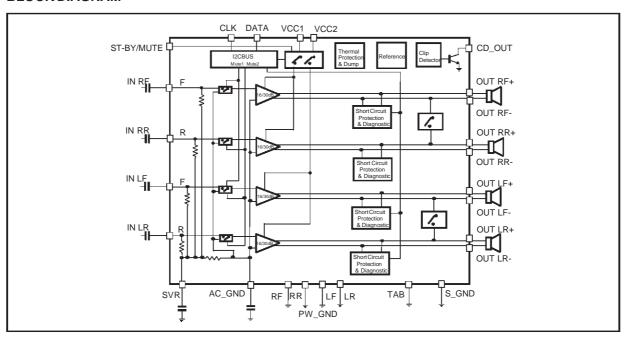


FLEXIWATT27

type of car radio amplifier in Flexiwatt27 package specially intended for car radio applications. Thanks to the DMOS output stage the TDA7563 has a very low distortion allowing a clear powerful sound. Among the features, its superior efficiency performance coming from the internal exclusive structure. makes it the most suitable device to simplify the thermal management in high power sets.

The dissipated output power under average listening condition is in fact reduced up to 50% when compared to the level provided by conventional class AB solutions.

This device is equipped with a full diagnostics array that communicates the status of each speaker through the I²C bus.



November 2001 1/20

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{op}	Operating Supply Voltage	18	V
Vs	DC Supply Voltage	28	V
V _{peak}	Peak Supply Voltage (for t = 50ms)	50	V
V _{CK}	CK pin Voltage	6	V
V _{DATA}	Data Pin Voltage	6	V
lo	Output Peak Current (not repetitive t = 100μs)	8	Α
Io	Output Peak Current (repetitive f > 10Hz)	6	Α
P _{tot}	Power Dissipation T _{case} = 70°C	85	W
T _{stg} , T _j	Storage and Junction Temperature	-55 to 150	°C

THERMAL DATA

Symbol	Description			Unit
R _{th j-case}	Thermal Resistance Junction-case	Max	1	°C/W

PIN CONNECTION

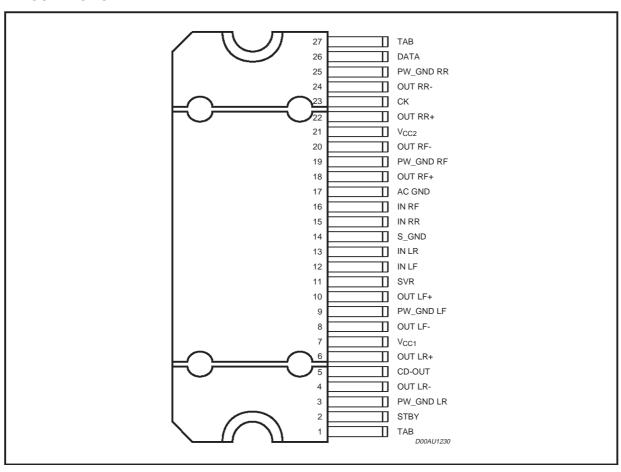
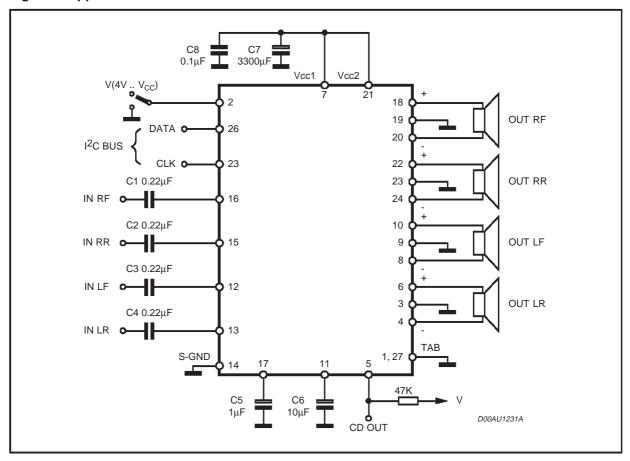


Figure 1. Application Circuit



ELECTRICAL CHARACTERISTICS (Refer to the test circuit, Vs = 14.4V; RL = 4Ω ; f = 1KHz; G_V = 30dB; T_{amb} = 25°C; unless otherwise specified.)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
POWER AI	MPLIFIER					
Vs	Supply Voltage Range		8		18	V
ld	Total Quiescent Drain Current			170	300	mA
Po	Output Power	EIAJ (Vs = 13.7V)	35	40		W
		THD = 10% THD = 1%	25	28 22		W W
		$\begin{array}{l} R_L = 2\Omega; \ \text{EIAJ} \ (\text{Vs} = 13.7\text{V}) \\ R_L = 2\Omega; \ \text{THD} \ 10\% \\ R_L = 2\Omega; \ \text{THD} \ 1\% \\ R_L = 2\Omega; \ \text{MAX} \ \text{POWER} \end{array}$	55 40	62 46 35 72		W W W
THD	Total Harmonic Distortion	Po = 1W to 10W; STD MODE HE MODE; Po = 1.5W HE MODE; Po = 8W		0.03 0.02 0.15	0.1 0.1 0.5	% % %
		Po = 1-10W, f = 10kHz		0.2	0.5	%
		$G_V = 16dB$; STD Mode $V_O = 0.1$ to 5VRMS		0.02	0.05	%
Ст	Cross Talk	$f = 1KHz$ to $10KHz$, $R_G = 600\Omega$	50	60		dB
Rin	Input Impedance		60	100	130	ΚΩ
Gv1	Voltage Gain 1		29.5	30	30.5	dB
∆Gv1	Voltage Gain Match 1		-1		1	dB
Gv2	Voltage Gain 2		15.5	16	16.5	dB
ΔG V2	Voltage Gain Match 2		-1		1	dB
EIN1	Output Noise Voltage 1	Rg = 600Ω 20Hz to 22kHz		50	100	μV
E _{IN2}	Output Noise Voltage 2	Rg = 600Ω ; Gv = $16dB$ 20Hz to $22kHz$		15	30	μV
SVR	Supply Voltage Rejection	$f = 100$ Hz to 10 kHz; $Vr = 1$ Vpk; $Rg = 600\Omega$	50	60		dB
BW	Power Bandwidth		100			KHz
Asa	Stand-by Attenuation		90	110		dB
Isa	Stand-by Current			2	100	μА
Ам	Mute Attenuation		80	100		dB
Vos	Offset Voltage	Mute & Play	-100	0	100	mV
V_{AM}	Min. Supply Mute Threshold		7	7.5	8	V
T _{ON}	Turn ON Delay	D2/D1 (IB1) 0 to 1		5	20	ms
T _{OFF}	Turn OFF Delay	D2/D1 (IB1) 1 to 0		5	20	ms
V_{SBY}	St-By/Mute pin for St-By		0		1.5	V
V_{MU}	St-By/Mute pin for Mute		3.5		5	V
V _{OP}	St-By/Mute pin for Operating		7		Vs	V
I _{MU}	St-By/Mute pin Current	V _{STBY/MUTE} = 8.5V		20	40	μΑ
		V _{STBY/MUTE} < 1.5V		0	10	μΑ
CD _{LK}	Clip Det High Leakage Current	CD off		0	15	μΑ
CD _{SAT}	Clip Det Sat. Voltage	CD on; ICD = 1mA		300		mV
CD _{THD}	Clip Det THD level	D0 (IB1) = 1	5	10	15	%
		D0 (IB1) = 0	1	2	3	%

ELECTRICAL CHARACTERISTICS (continued)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
Pgnd	Short to GND det. (below this limit, the Output is considered in Short Circuit to GND)	Power Amplifier in st-by			1.2	V
Pvs	Short to Vs det. (above this limit, the Output isconsidered in Short Circuit to Vs)		Vs -1.2			V
Pnop	Normal operation thresholds. (Within these limits, the Output is considered without faults).		1.8		Vs -1.8	V
Lsc	Shorted Load det.				0.5	Ω
Lop	Open Load det.		130			Ω
Lnop	Normal Load det.		1.5		70	Ω
TURN ON	DIAGNOSTICS 2 (Line Driver I	Mode)				
Pgnd	Short to GND det. (below this limit, the Output is considered in Short Circuit to GND)	Power Amplifier in st-by			1.2	V
Pvs	Short to Vs det. (above this limit, the Output isconsidered in Short Circuit to Vs)		Vs -1.2			V
Pnop	Normal operation thresholds. (Within these limits, the Output is considered without faults).		1.8		Vs -1.8	V
Lsc	Shorted Load det.				1.5	Ω
Lop	Open Load det.		400			Ω
Lnop	Normal Load det.		4.5		200	Ω
PERMANE	NT DIAGNOSTICS 2 (Power A	Amplifier Mode or Line Driver N	/lode)			
Pgnd	Short to GND det. (below this limit, the Output is considered in Short Circuit to GND)	Power Amplifier in Mute or Play, one or more short circuits protection activated			1.2	V
Pvs	Short to Vs det. (above this limit, the Output is considered in Short Circuit to Vs)		Vs -1.2			V
Pnop	Normal operation thresholds. (Within these limits, the Output is considered without faults).		1.8		Vs -1.8	V
L _{SC}	Shorted Load Det.	Pow. Amp. mode			0.5	Ω
		Line Driver mode			1.5	Ω
Vo	Offset Detection	Power Amplifier in play, AC Input signals = 0	±1.5	±2	±2.5	V
² C BUS IN	ITERFACE					
fscL	Clock Frequency				400	KHz
VIL	Input Low Voltage				1.5	V
	Input High Voltage					

Figure 2. Quiescent Current vs. Supply Voltage

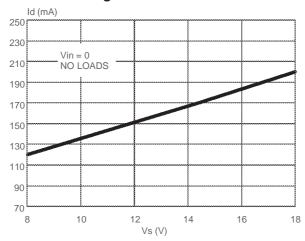


Figure 3. Output Power vs. Supply Voltage (4 Ω)

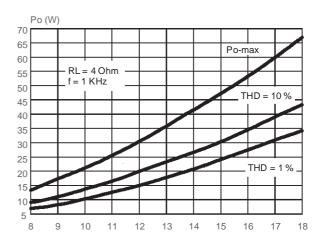


Figure 4. Output Power vs. Supply Voltage (2 Ω)

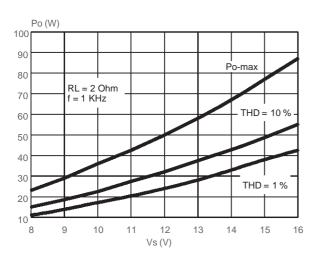


Figure 5. Distortion vs. Output Power (4Ω , STD)

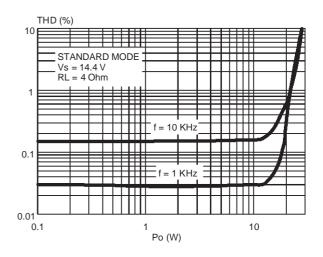


Figure 6. Distortion vs. Output Power $(4\Omega, HI-EFF)$

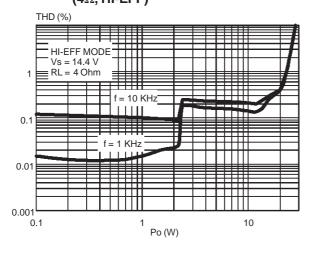


Figure 7. Distortion vs. Output Power (2 Ω , STD)

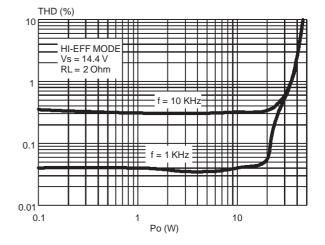


Figure 8. Distortion vs. Frequency (4 Ω)

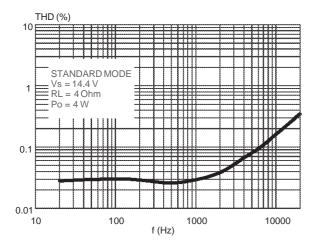


Figure 10. Crosstalk vs. Frequency

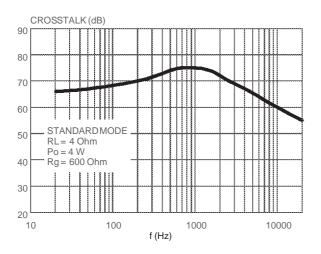


Figure 12. Power Dissipation & Efficiency vs. Output Power (4Ω , STD, SINE)

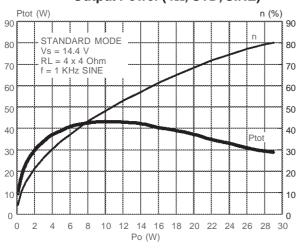


Figure 9. Distortion vs. Frequency (2 Ω)

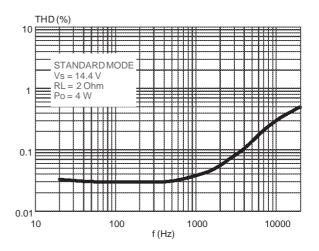


Figure 11. Supply Voltage Rejection vs. Frequency

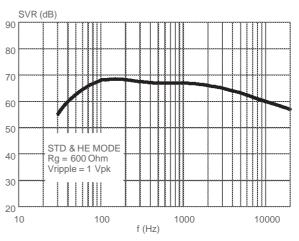


Figure 13. Power Dissipation & Efficiency vs. Output Power (4Ω , HI-EFF, SINE)

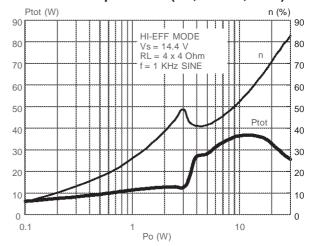


Figure 14. Power Dissipation vs. Average Ouput Power (Audio Program Simulation, 4Ω)

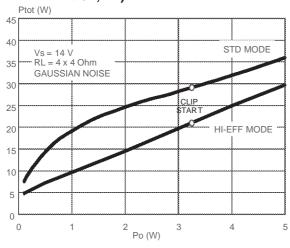
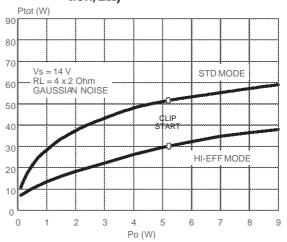


Figure 15. Power Dissipation vs. Average Ouput Power (Audio Program Simulation, $\mathbf{2}\Omega$)



DIAGNOSTICS FUNCTIONAL DESCRIPTION: a) TURN-ON DIAGNOSTIC.

It is activated at the turn-on (stand-by out) under I2Cbus request. Detectable output faults are:

- SHORT TO GND
- SHORT TO Vs
- SHORT ACROSS THE SPEAKER
- OPEN SPEAKER

To verify if any of the above misconnections are in place, a subsonic (inaudible) current pulse (fig. 16) is internally generated, sent through the

speaker(s) and sunk back. The Turn On diagnostic status is internally stored until a successive diagnostic pulse is requested (after a I2C reading).

If the "stand-by out" and "diag. enable" commands are both given through a single programming step, the pulse takes place first (power stage still in stand-by mode, low, outputs= high impedance).

Afterwards, when the Amplifier is biased, the PERMANENT diagnostic takes place. The previous Turn On state is kept until a short appears at the outputs.

Figure 16. Turn - On diagnostic: working principle

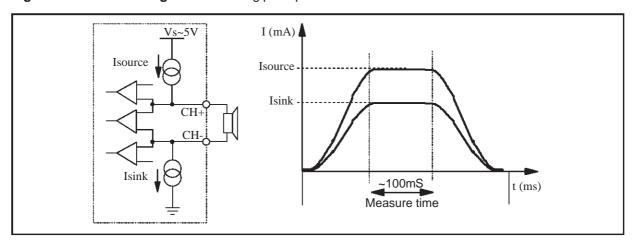


Fig. 17 and 18 show SVR and OUTPUT waveforms at the turn-on (stand-by out) with and without TURN-ON DIAGNOSTIC.

Figure 17. SVR and Output behaviour

CASE 1: without turn-on diagnostic

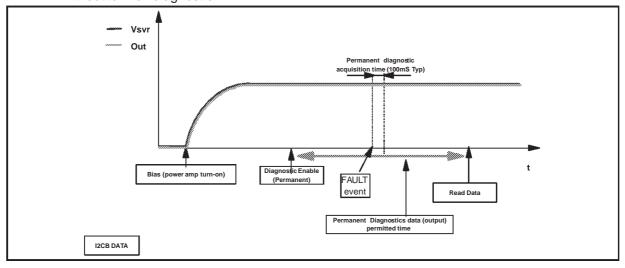
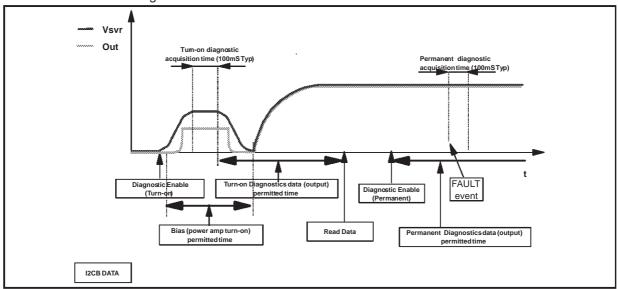
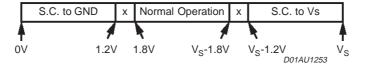


Figure 18. SVR and Output pin behaviour

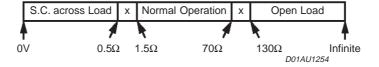
CASE 2: with turn-on diagnostic



The information related to the outputs status is read and memorized at the end of the current pulse top. The acquisition time is 100 ms (typ.). No audible noise is generated in the process. As for SHORT TO GND / Vs the fault-detection thresholds remain unchanged from 30 dB to 16 dB gain setting. They are as follows:



Concerning SHORT ACROSS THE SPEAKER / OPEN SPEAKER, the threshold varies from 30 dB to 16 dB gain setting, since different loads are expected (either normal speaker's impedance or high impedance). The values in case of 30 dB gain are as follows:



If the Line-Driver mode (Gv= 16 dB and Line Driver Mode diagnostic = 1) is selected, the same thresholds will change as follows:



5

b) PERMANENT DIAGNOSTICS.

Detectable conventional faults are:

- SHORT TO GND
- SHORT TO Vs
- SHORT ACROSS THE SPEAKER

The following additional features are provided:

- OUTPUT OFFSET DETECTION

The TDA7563 has 2 operating statuses:

- 1) RESTART mode. The diagnostic is not enabled. Each audio channel operates independently from each other. If any of the a.m. faults occurs, only the channel(s) interested is shut down. A check of the output status is made every 1 ms (fig. 19). Restart takes place when the overload is removed.
- 2) DIAGNOSTIC mode. It is enabled via I2C bus and self activates if an output overload (such to cause the intervention of the short-circuit protection) occurs to the speakers outputs. Once activated, the diagnostics procedure develops as fol-

lows (fig. 20):

- To avoid momentary re-circulation spikes from giving erroneous diagnostics, a check of the output status is made after 1ms: if normal situation (no overloads) is detected, the diagnostic is not performed and the channel returns back active.
- -Instead, if an overload is detected during the check after 1 ms, then a diagnostic cycle having a duration of about 100 ms is started.
- -After a diagnostic cycle, the audio channel interested by the fault is switched to RESTART mode. The relevant data are stored inside the device and can be read by the microprocessor. When one cycle has terminated, the next one is activated by an I²C reading. This is to ensure continuous diagnostics throughout the car-radio operating time.
- -To check the status of the device a sampling system is needed. The timing is chosen at microprocessor level (over half a second is recommended).

Figure 19. Restart timing without Diagnostic Enable (Permanent) Each 1mS time, a sampling of the fault is done

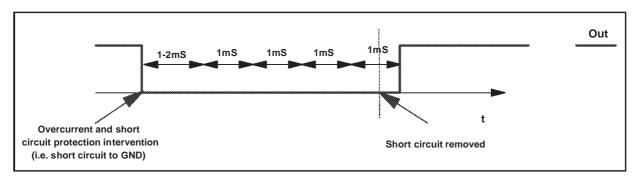
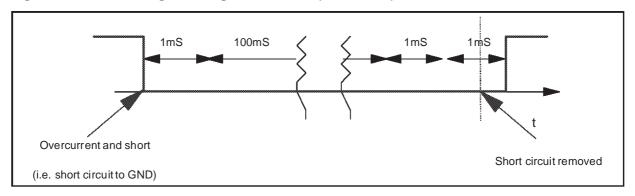


Figure 20. Restart timing with Diagnostic Enable (Permanent)



OUTPUT DC OFFSET DETECTION.

Any DC output offset exceeding +/- 2 V are signalled out. This inconvenient might occur as a consequence of initially defective or aged and worn-out input capacitors feeding a DC component to the inputs, so putting the speakers at risk of overheating.

This diagnostic has to be performed with low-level output AC signal (or Vin = 0).

The test is run with selectable time duration by microprocessor (from a "start" to a "stop" command):

START = Last reading operation or setting IB1 - D5 - (OFFSET enable) to 1

STOP = Actual reading operation

Excess offset is signalled out if persistent throughout the assigned testing time. This feature is disabled if any overloads leading to activation of the short-circuit protection occurs in the process.

MULTIPLE FAULTS.

When more misconnections are simultaneously in place at the audio outputs, it is guaranteed that at least one of them is initially read out. The others are notified after successive cycles of ¹²C reading and faults removal, provided that the diagnostic is enabled. This is true for both kinds of diagnostic (Turn on and Permanent).

The table below shows all the couples of double-fault possible. It should be taken into account that a short circuit with the 4 ohm speaker unconnected is considered as double fault.

Double fault table for Turn On Diagnostic							
	S. GND (so)	S. GND (sk)	S. Vs	S. Across L.	Open L.		
S. GND (so)	S. GND	S. GND	S. Vs + S. GND	S. GND	S. GND		
S. GND (sk)	/	S. GND	S. Vs	S. GND	Open L. (*)		
S. Vs	/	/	S. Vs	S. Vs	S. Vs		
S. Across L.	/	/	/	S. Across L.	N.A.		
Open L.	/	/	/	/	Open L. (*)		

S. GND (so) / S. GND (sk) in the above table make a distinction according to which of the 2 outputs is shorted to ground (test-current source side= so, test-current sink side = sk). More precisely, in Channels LF and RR, so = CH+, sk = CH-; in Channels LR and RF, so = CH-, sk = CH+

In Permanent Diagnostic the table is the same, with only a difference concerning Open Load(*), which is not among the recognisable faults. Should an Open Load be present during the device's normal working, it would be detected at a subsequent Turn on Diagnostic cycle (i.e. at the successive Car Radio Turn on).

FAULTS AVAILABILITY

All the results coming from I²Cbus, by read operations, are the consequence of measurements inside a defined period of time. If the fault is stable throughout the whole period, it will be sent out.

To guarantee always resident functions, every kind of diagnostic cycles (Turn on, Permanent, Offset) will be reactivate after any I²C reading operation. So, when the micro reads the I²C, a new cycle will be able to start, but the read data will come from the previous diag. cycle (i.e. The device is in Turn On state, with a short to Gnd, then

the short is removed and micro reads I^2C . The short to Gnd is still present in bytes, because it is the result of the previous cycle. If another I^2C reading operation occurs, the bytes do not show the short). In general to observe a change in Diagnostic bytes, two I^2C reading operations are necessary.

THERMAL PROTECTION

Thermal protection is implemented through thermal foldback (fig. 21). Thermal foldback begins limiting the audio input to the amplifier stage as the junction temperatures rise above the normal operating range. This effectively limits the output power capability of the device thus reducing the temperature to acceptable levels without totally interrupting the operation of the device. The output power will decrease to the point at which thermal equilibrium is reached. Thermal equilibrium will be reached when the reduction in output power reduces the dissipated power such that the die temperature falls below the thermal foldback threshold. Should the device cool, the audio level will increase until a new thermal equilibrium is reached or the amplifier reaches full power. Thermal foldback will reduce the audio output level in a linear manner.

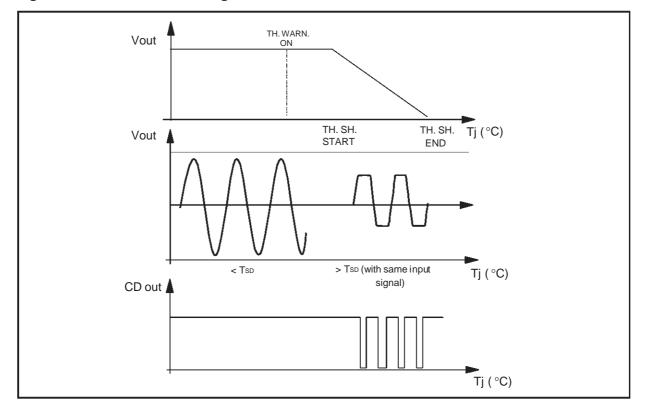


Figure 21. Thermal Foldback Diagram

I²C PROGRAMMING/READING SEQUENCES

A correct turn on/off sequence respectful of the diagnostic timings and producing no audible noises could be as follows (after battery connection):

TURN-ON: PIN2 > 7V --- 10ms --- (STAND-BY OUT + DIAG ENABLE) --- 500 ms (min) --- MUT-ING OUT

TURN-OFF: MUTING IN --- 20 ms --- (DIAG DIS-

ABLE + STAND-BY IN) --- 10ms --- PIN2 = 0 Car Radio Installation: PIN2 > 7V --- 10ms DIAG ENABLE (write) --- 200 ms --- I^2 C read (repeat until All faults disappear).

OFFSET TEST: Device in Play (no signal) -- OFFSET ENABLE - 30ms - I²C reading (repeat I²C reading until high-offset message disappears).

I²C BUSINTERFACE

Data transmission from microprocessor to the TDA7563 and viceversa takes place through the 2 wires I²C BUS interface, consisting of the two lines SDA and SCL (pull-up resistors to positive supply voltage must be connected).

Data Validity

As shown by fig. 22, the data on the SDA line must be stable during the high period of the clock.

The HIGH and LOW state of the data line can only change when the clock signal on the SCL line is LOW.

Start and Stop Conditions

As shown by fig. 23 a start condition is a HIGH to LOW transition of the SDA line while SCL is HIGH.

The stop condition is a LOW to HIGH transition of the SDA line while SCL is HIGH.

Byte Format

Every byte transferred to the SDA line must contain 8 bits. Each byte must be followed by an acknowledge bit. The MSB is transferred first.

Acknowledge

The transmitter* puts a resistive HIGH level on the SDA line during the acknowledge clock pulse (see fig. 24). The receiver** the acknowledges has to pull-down (LOW) the SDA line during the acknowledge clock pulse, so that the SDAline is stable LOW during this clock pulse.

* Transmitter

- = master (μP) when it writes an address to the TDA7563
- = slave (TDA7563) when the μP reads a data byte from TDA7563

** Receiver

- = slave (TDA7563) when the μP writes an address to the TDA7563
- = master (μ P) when it reads a data byte from TDA7563

Figure 22: Data Validity on the I²CBUS

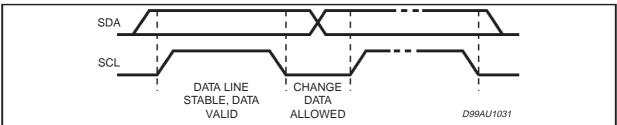


Figure 23: Timing Diagram on the I²CBUS

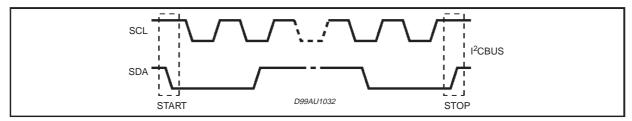
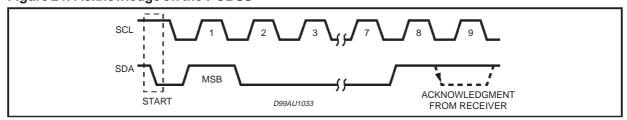


Figure 24: Acknowledge on the I²CBUS



SOFTWARE SPECIFICATIONS

All the functions of the TDA7563 are activated by $\mbox{I}^2\mbox{C}$ interface.

The bit 0 of the "ADDRESS BYTE" defines if the next bytes are $\,$ write instruction (from μP to TDA7563) or read instruction (from TDA7563 to μP).

Chip Address:

D7							D0	
1	1	0	1	1	0	0	Х	D8 Hex

X = 0 Write to device

X = 1 Read from device

If R/W = 0, the μ P sends 2 "Instruction Bytes": IB1 and IB2.

IB1

D7	X
D6	Diagnostic enable (D6 = 1) Diagnostic defeat (D6 = 0)
D5	Offset Detection enable (D5 = 1) Offset Detection defeat (D5 = 0)
D4	Front Channel Gain = 30dB (D4 = 0) Gain = 16dB (D4 = 1)
D3	Rear Channel Gain = 30dB (D3 = 0) Gain = 16dB (D3 = 1)
D2	Mute front channels (D2 = 0) Unmute front channels (D2 = 1)
D1	Mute rear channels (D1 = 0) Unmute rear channels (D1 = 1)
D0	CD 2% (D0 = 0) CD 10% (D0 = 1)

IB2

D7	X
D6	used for testing
D5	used for testing
D4	Stand-by on - Amplifier not working - (D4 = 0) Stand-by off - Amplifier working - (D4 = 1)
D3	Power amplifier mode diagnostic (D3 = 0) Line driver mode diagnostic (D3 = 1)
D2	X
D1	Right Channel Power amplifier working in standard mode (D1 = 0) Power amplifier working in high efficiency mode (D1 = 1)
D0	Left Channel Power amplifier working in standard mode (D0 = 0) Power amplifier working in high efficiency mode (D0 = 1)

TDA7563

If R/W = 1, the TDA7563 sends 4 "Diagnostics Bytes" to μP : DB1, DB2, DB3 and DB4. **DB1**

D7	Thermal warning active (D7 = 1)
D6	Diag. cycle not activated or not terminated (D6 = 0) Diag. cycle terminated (D6 = 1)
D5	X
D4	Channel LF Turn-on diagnostic (D4 = 0) Permanent diagnostic (D4 = 1)
D3	Channel LF Normal load (D3 = 0) Short load (D3 = 1)
D2	Channel LF Turn-on diag.: No open load (D2 = 0) Open load detection (D2 = 1) Offset diag.: No output offset (D2 = 0) Output offset detection (D2 = 1)
D1	Channel LF No short to Vcc (D1 = 0) Short to Vcc (D1 = 1)
D0	Channel LF No short to GND (D1 = 0) Short to GND (D1 = 1)

DB2

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D7	Offset detection not activated (D7 = 0) Offset detection activated (D7 = 1)
D6	X
D5	X
D4	Channel LR Turn-on diagnostic (D4 = 0) Permanent diagnostic (D4 = 1)
D3	Channel LR Normal load (D3 = 0) Short load (D3 = 1)
D2	Channel LR Turn-on diag.: No open load (D2 = 0) Open load detection (D2 = 1) Permanent diag.: No output offset (D2 = 0) Output offset detection (D2 = 1)
D1	Channel LR No short to Vcc (D1 = 0) Short to Vcc (D1 = 1)
D0	Channel LR No short to GND (D1 = 0) Short to GND (D1 = 1)

DB3

D7	Stand-by status (= IB1 - D4)
D6	Diagnostic status (= IB1 - D6)
D5	X
D4	Channel RF Turn-on diagnostic (D4 = 0) Permanent diagnostic (D4 = 1)
D3	Channel RF Normal load (D3 = 0) Short load (D3 = 1)
D2	Channel RF Turn-on diag.: No open load (D2 = 0) Open load detection (D2 = 1) Permanent diag.: No output offset (D2 = 0) Output offset detection (D2 = 1)
D1	Channel RF No short to Vcc (D1 = 0) Short to Vcc (D1 = 1)
D0	Channel RF No short to GND (D1 = 0) Short to GND (D1 = 1)

DB4

D7	X
D6	X
D5	X
D4	Channel RR Turn-on diagnostic (D4 = 0) Permanent diagnostic (D4 = 1)
D3	Channel RR Normal load (D3 = 0) Short load (D3 = 1)
D2	Channel RR Turn-on diag.: No open load (D2 = 0) Open load detection (D2 = 1) Permanent diag.: No output offset (D2 = 0) Output offset detection (D2 = 1)
D1	Channel RR No short to Vcc (D1 = 0) Short to Vcc (D1 = 1)
D0	Channel RR No short to GND (D1 = 0) Short to GND (D1 = 1)

Examples of bytes sequence

1 - Turn-On diagnostic - Write operation

1	Start	Address byte with D0 = 0	ACK	IB1 with D6 = 1	ACK	IB2	ACK	STOP
- 1	Otart	Address byte with bo = 0	I AON	IDI WILII DO — I	ACK	102	AON	3101

2 - Turn-On diagnostic - Read operation

Start Address byte with D0 = 1 ACK DB1 ACK DB2 ACK	C DB3 ACK DB4 ACK STOP
--	------------------------

The delay from 1 to 2 can be selected by software, starting from T.B.D. ms

3a - Turn-On of the power amplifier with 30dB gain, mute on, diagnostic defeat, CD = 2%.

Start	Address byte with D0 = 0	ACK	IB1	ACK	IB2	ACK	STOP
		X0000000		XXX1XX11			

3b - Turn-Off of the power amplifier

Start	Address byte with D0 = 0	ACK	IB1	ACK	IB2	ACK	STOP
			X0XXXXXX		XXX0XXXX		

4 - Offset detection procedure enable

Start	Address byte with D0 = 0	ACK	IB1	ACK	IB2	ACK	STOP
		XX1XX11X		XXX1XXXX			

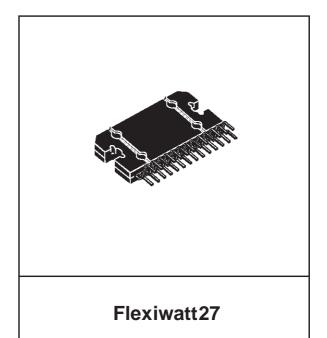
5 - Offset detection procedure stop and reading operation (the results are valid only for the offset detection bits (D2 of the bytes DB1, DB2, DB3, DB4).

Start Address byte with D0 = 1 ACK DB1 ACK DB2 ACK DB3 ACK DB4 ACK	STOP
--	------

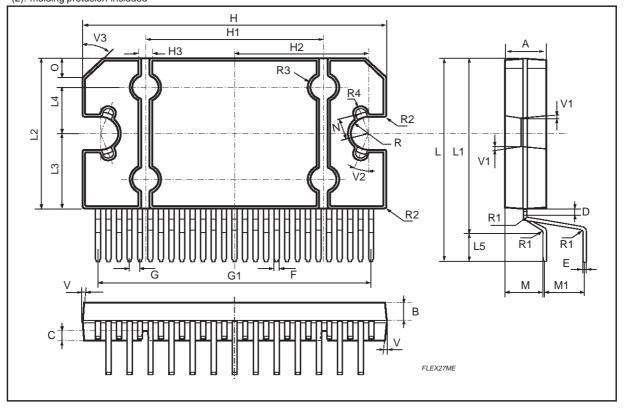
- The purpose of this test is to check if a D.C. offset (2V typ.) is present on the outputs, produced by input capacitor with anomalous leackage current or humidity between pins.
- The delay from 4 to 5 can be selected by software, starting from T.B.D. ms

DIM.	mm inch							
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
А	4.45	4.50	4.65	0.175	0.177	0.183		
В	1.80	1.90	2.00	0.070	0.074	0.079		
С		1.40			0.055			
D	0.75	0.90	1.05	0.029	0.035	0.041		
Е	0.37	0.39	0.42	0.014	0.015	0.016		
F (1)			0.57			0.022		
G	0.80	1.00	1.20	0.031	0.040	0.047		
G1	25.75	26.00	26.25	1.014	1.023	1.033		
H (2)	28.90	29.23	29.30	1.139	1.150	1.153		
H1		17.00			0.669			
H2		12.80			0.503			
H3		0.80			0.031			
L (2)	22.07	22.47	22.87	0.869	0.884	0.904		
L1	18.57	18.97	19.37	0.731	0.747	0.762		
L2 (2)	15.50	15.70	15.90	0.610	0.618	0.626		
L3	7.70	7.85	7.95	0.303	0.309	0.313		
L4		5			0.197			
L5	3.5 3.70 4.00				0.138			
М			4.30	0.145	0.157	0.169		
M1	3.60	4.00	4.40	0.142	0.157	0.173		
N		2.20			0.086			
0		2			0.079			
R		1.70			0.067			
R1		0.5			0.02			
R2		0.3			0.12			
R3	1.25				0.049			
R4		0.50		0.019				
V	5° (Тур.)							
V1	3° (Typ.)							
V2			20° (Тур.)				
V3	45° (Typ.)							

OUTLINE AND MECHANICAL DATA



(1): dam-bar protusion not included (2): molding protusion included



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